## NTID Automation Technologies Program Outcomes Assessment Plan and Report for AY 2005-06\*

Program Goal: To provide students the job entry skills needed to acquire positions in a wide array of automated environments, who will have as their primary responsibilities, to install, maintain, upgrade, troubleshoot and repair automated systems and their components.

Critical Outcomes for all Students		Assessment of Outcomes		Timeline		Results	
Domain/Task/ Capability	Performance Criteria/ Benchmarks	Instrument/ Opportunity	Assessment of Performance	Develop	Collect	Summarization of Results	Use of Results
Subsystem Capability	<ul> <li>A. Use of Tools: Students will be able to identify and demonstrate correct use of tools.</li> <li>B. Safety Awareness: Students will be able to describe and demonstrate correct safety protocols.</li> <li>C. Reading and interpreting drawings, schematics and technical specs: Students will demonstrate the ability to read and correctly interpret electrical and mechanical drawings, schematics and technical specs: Students will demonstrate the ability to read and correctly interpret electrical and mechanical drawings, schematics and technical specifications sheets.</li> <li>D. Programming: Students will demonstrate an understanding of programming concepts relating to the control of a system or process.</li> </ul>	Benchmarks A- F Assessment to occur as a written and hands-on project exam at the end of the Automated Systems I course, (0891- 220) Fall quarter of the second year.	<ul> <li>A. Given an assembly or disassembly project, the all students will be able to identify and correctly use 90% of the tools needed.</li> <li>B. Given a scenario of an automated environment, all students will be able to describe the correct safety protocol and demonstrate adherence to the safety protocol on a given project 100% of the time.</li> <li>C. Given an assembly or troubleshooting project, all students will be able to correctly read and interpret electrical and mechanical drawings, schematics and other technical specification sheets needed to correctly assemble or troubleshoot the equipment 80% of the time.</li> <li>D. Given written program segments, all of the students</li> </ul>	A-F 20033	A-F 20041		

	Instrumentation: Students will demonstrate the ability to correctly select, use and interpret instrumentation measurement devices. F. Problem Solving: Students will demonstrate a logical approach to problem solving and document solutions.		<ul> <li>will be able to determine the function or purpose of the program segment 80% of the time.</li> <li>E. Given a project requiring electrical or mechanical gauges, all students will be able to correctly select, connect, and accurately read gauges information or electrical measurement information 80% of the time.</li> <li>F. Given a series of subsystems having one or more problems, all students will be able to demonstrate a logical approach to solving the problem(s), and will document the solution 80% of the time.</li> </ul>			
System Level Capability						
Robotics Option Subsystem Integration	A. Assembling: Students will correctly assemble a basic automated system using mechanical and electrical drawings and manuals. Such system(s) may include subsystems such as motion controllers, HMI's, Robotic Controllers, Pneumatic and Hydraulic modules and various electromechanical sensing/signaling	Benchmarks A- G Assessment to occur as a written and hands-on project exam at the end of the Automated Systems Troubleshooting II course, (0891-330) Fall quarter of the third year.	<ul> <li>A. Given a basic system, all students will mechanically and electrically assemble additional subsystems onto the system using mechanical and electrical drawings and manuals with minimal supervision.</li> <li>B. Given the assembled system, all students will be able to identify interface types, select appropriate interface connectors and connect and configure the</li> </ul>	A-G 20033	A-G 20041	

## devices.

B. Interfacing: Students will identify different electrical and mechanical interfaces and understand supporting documentation.

C. *Programming:* Students will correctly install and debug simple controller programs.

D. Safety Awareness: Students will be able to demonstrate correct safety protocols and procedures.

## E.

*Troubleshooting:* Students will demonstrate a logical approach to troubleshooting and repairing system faults.

F. Data Collection and Process Verification: Students will be able to demonstrate correct use and interpretation of basic quality control and statistical analysis tools and techniques.

G. System Maintenance: Students will be able to identify and describe system interface with 80% accuracy.

C. Given a connected/interfaced controller all students will be able to install controller program(s) and will be able to debug 80% of the a simple controller program errors.

D. Given a operating automated system senerio or actual system set-up, all students will be able to describe the correct safety protocol/procedures and demonstrate adherence to them on a given project 100% of the time.

E. Given an automated system with operating faults, all students will be able to demonstrate a logical approach to troubleshooting and be able to identify and repair 80% of the faults.

F. Given an operating automated system, all students will be able to collect process data and demonstrate use of control charts or other statistical analysis tools and techniques to verify process control compliance (or lack of it) with 80% accuracy.

G. Given an automated system, all students will be able to identify and

	maintenance requirements and perform basic maintenance tasks.		describe 80% of the maintenance tasks required for the system and correctly perform those maintenance tasks.			
Semiconductor Option Subsystem Integration	A. Interfacing:Students willidentify differentelectrical andmechanicalinterfaces andunderstandsupportingdocumentation.B. Programming:Students willcorrectly installand debug simplecontrollerprograms.C. SafetyAwareness:Students will beable to describeand demonstratecorrect safetyprotocols andproceduresrelated tochemical andequipment safetyusing the MaterialSafety DataSheets (MSDS).D.Troubleshooting:Students willdemonstrate alogical approachto troubleshootingand repairingsystem faultsusing supportingdocumentation.E. DataCollection andProcessVerification:Students will beable todemonstratecorrect use and	<i>Benchmarks A-H</i> Assessment to occur as a written and hands-on project exam at the end of the Semiconductor Tooling course, (0891-350) Fall quarter of the third year.	A. Given the assembled system, all students will be able to identify interface types, and configure the interface with 80% accuracy. B. Given a connected/interfaced controller all students will be able to install controller program(s) and will be able to debug 80% of the simple controller program errors. C. Given an operating automated system scenario or actual system set-up, all students will be able to describe the correct safety protocol/procedures and demonstrate adherence to them on a given project 100% of the time. D. Given an automated system with operating faults, all students will be able to demonstrate a logical approach to troubleshooting and be able to identify and repair 80% of the faults using the supporting documentation.	A-H 20033	A-H 20041	
11	interpretation of		will be able to			

basic quality	collect process data		
control and	and demonstrate use		
statistical analysis	of control charts or		
tools and	other statistical		
techniques.	analysis tools and		
	techniques to verify		
F. System	process control		
Maintenance:	compliance (or lack		
Students will be	of it) with 80%		
able to identify	accuracy.		
and describe			
system	F. Given an		
maintenance	automated system,		
requirements and	all students will be		
perform basic	able to identify and		
maintenance	describe 80% of the		
tasks.	maintenance tasks		
	required for the		
G. Wafer	system and correctly		
Fabrication	perform those		
Process: Students	maintenance tasks.		
will be able to			
flowchart and	G. All students will		
describe the	be able to flowchart		
process for	and describe the		
fabricating	process for		
wafers.	fabricating wafers		
	with 100% accuracy.		
H. Clean Room			
Protocol:	H. Given a clean		
Students will	room environment		
correctly describe	or scenario, all		
and demonstrate	students will be able		
clean room	to correctly describe		
protocol.	and demonstrate		
	appropriate clean		
	room protocol 100		
	% of the time.		

## **Comments:**

\*The curriculum for this program of study was modified during AY 2005-06 and a new Outcomes Assessment Plan was written. Data for the new plan will be collected and reported for students who enter the modified program beginning AY 2006-07.

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